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Thomas E. Tiwald University of Nebraska - Lincoln

William A. McGahan University of Nebraska - Lincoln

Z. S. Shan University of Nebraska - Lincoln

Alan M. Massengale University of Nebraska - Lincoln

John A. Woollam University of Nebraska - Lincoln

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### Variable angle spectroscopic magneto-optics and ellipsometry: Application to DyCo multilayers (abstract)

Thomas E. Tiwald William A. McGahan Z. S. Shan Alan M. Massengale John A. Woollam

Departments of Electrical Engineering and Physics, University of Nebraska, Lincoln, Nebraska 68588-0511

#### **Abstract**

The purpose of this paper is twofold. First, we describe the adaptation of a variable angle spectroscopic ellipsometer (VASE) to magneto-optic measurements covering 3000–8000 Å, and 0 to  $\pm 8$  kOe. Second, we describe application of VASE to determine Kerr rotation and ellipticity for a series of Dy/Co multilayers prepared by sputter deposition. We report spectroscopic ellipsometric and Kerr effect results for samples exhibiting perpendicular magnetic anisotropy, since these are relevant as magneto-optic recording media.

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